

SEMICONDUCTOR

FCH35N60 600V N-Channel MOSFET

Features

- 650V @ T_J = 150°C
- Typ.R_{DS(on)} = 0.079Ω
- Ultra low gate charge (Typ. Q_g = 139nC)
- Low effective output capacitance (Typ. C_{oss}.eff = 340pF)
- 100% avalanche tested

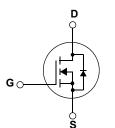


Description

SuperFETTM is Farichild's proprietary, new generation of high voltage MOSFET family that is utilizing an advanced charge balance mechanism for outstanding low on-resistance and lower gate charge performance.

This advanced technology has been tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate and higher avalanche energy. Consequently, SuperFET is very suitable for various AC/DC power conversion in switching mode operation for system miniaturization and higher efficiency.





MOSFET Maximum Ratings T_C = 25°C unless otherwise noted*

Symbol		Parameter	Ratings	Units		
V _{DSS}	Drain to Source Voltage	rain to Source Voltage				
V _{GSS}	Gate-Soure voltage			±30	V	
ID	Drain Current	-Continuous (T _C = 25 ^o C)	-Continuous (T _C = 25 ^o C)		^	
	DrainCurrent	-Continuous (T _C = 100 ^o C)		22.2	— A	
I _{DM}	Drain Current	- Pulsed	- Pulsed (Note 1)			
E _{AS}	Single Pulsed Avalanche Energy (Note		(Note 2)	1455	mJ	
I _{AR}	Avalanche Current		(Note 1)	35	А	
E _{AR}	Repetitive Avalanche Energy		(Note 1)	31.25	mJ	
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	20	V/ns	
P _D	Dewer Dissinction	(T _C = 25°C)		312.5	W	
	Power Dissipation	- Derate above 25 ^o C		2.5	W/ºC	
T _J , T _{STG}	Operating and Storage Temperature Range			-55 to +150	°C	
TL	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			300	°C	

Thermal Characteristics

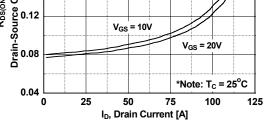
Symbol	Parameter	Тур.	Max.	Units
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case	-	0.4	
$R_{\theta CS}$	CS Thermal Resistance, Case-to-Heat Sink		-	°C/W
$R_{ ext{ heta}JA}$	Thermal Resistance, Junction to Ambient	-	42	

February 2010

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Device Marking FCH35N60		Device FCH35N60	Packa TO-24	·		e Width Qu		Quantit 30	•	
Electrica	al Chara	acteristics								
Symbol		Parameter			Test Conditions		Min.	Тур.	Max.	Units
Off Chara	cteristics	5								
BV _{DSS}	Drain to Source Breakdown Voltage		$I_D = 250 \mu A, V_{GS} = 0V, T_J = 25^{\circ}C$ $I_D = 250 \mu A, V_{GS} = 0V, T_J = 150^{\circ}C$		600	- 650	-	V		
ΔBV _{DSS} / ΔT	Breakdo	akdown Voltage Temperature fficient			50μA, Referenced to 2		-	0.6	-	V/°C
BV _{DS}	Drain-Source Avalanche Breakdown Voltage			V _{GS} =	0V, I _D = 16A		-	700	-	V
1	7			V _{DS} =	600V, V _{GS} = 0V		-	-	1	•
DSS	zero Ga	ite Voltage Drain Curr	ent		480V, T _C = 125 ^o C		-	-	10	μA
I _{GSS}	Gate to	Body Leakage Curre	nt	V _{GS} =	±30V, V _{DS} = 0V		-	-	±100	nA
On Charao				- T						
V _{GS(th)}		reshold Voltage			· V _{DS} , I _D = 250μA		3.0	-	5.0	V
R _{DS(on)}					= 10V, I _D = 17.5A		-	0.079	0.098	Ω
FS	Forward Transconductance			V _{DS} =	40V, I _D = 17.5A		-	28.8	-	S
Oynamic (Characte	eristics								
C _{iss}	1	apacitance					-	4990	6640	pF
C _{oss}	Output C	It Capacitance rse Transfer Capacitance			25V, V _{GS} = 0V	-	-	2380	3170	pF
C _{rss}	Reverse			f = 1N	IHZ	-	-	140	-	pF
C _{oss}	Output C	Itput Capacitance			480V, V _{GS} = 0V, f = 1	1.0MHz	-	113	-	pF
C _{oss} eff.	Effective	Effective Output Capacitance			$0V \text{ to } 480V, V_{GS} = 0^{10}$		-	340	-	pF
Q _g	Total Ga	Total Gate Charge at 10V					-	139	181	nC
ຊ _{gs}	Gate to	e to Source Gate Charge		V _{DS} = 480V, I _D = 35A		-	31	-	nC	
Q _{gd}	Gate to	e to Drain "Miller" Charge		V _{GS} =	: 10V	(Nata 4)	-	69	-	nC
ESR		Equivalent Series Resistance (G-S)		Drain	Open, F= 1MHZ	(Note 4)	-	1.4	_	Ω
			(0-0)	Drain			-	1.4	-	52
Switching				1			1		1	T
d(on)		D = 170		00011	_	-	34	78	ns	
r					$V_{DD} = 300V, I_D = 35A$ R _G = 4.7Ω		-	120	250	ns
d(off)			_	-	105	220	ns			
f	Turn-Off	Fall Time				(Note 4)	-	73	155	ns
)rain-Sou	rce Diod	le Characteristic	s							
S	Maximum Continuous Drain to Source Diode Forward Current					-	-	35	Α	
SM	Maximur	Maximum Pulsed Drain to Source Diode Fo			urrent		-	-	105	Α
V _{SD}	Drain to	Drain to Source Diode Forward Voltage		V _{GS} =	$V_{GS} = 0V, I_{SD} = 35A$		-	-	1.4	V
rr	Reverse	Recovery Time		V _{GS} =	0V, I _{SD} = 35A		-	614	-	ns
11	-				= 100Å/µs	F	-	16.3	-	μC

查询"FCH35N60"供应商 **Typical Performance Characteristics Figure 1. On-Region Characteristics** 200 V_{GS} = 15.0 V 100 10.0 V 8.0 V 7.0 V 6.5 V l_b, Drain Current[A] 6.0 V 5.5 V 10 1 Notes: 1. 250µs Pulse Test 2. T_C = 25^oC 0.3 L 0.1 10 20 1 V_{DS}, Drain-Source Voltage[V] Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage 0.24 Drain-Source On-Resistance 0.16 0.12 0.02 0.02 $R_{DS(ON)}$ [Ω], $V_{GS} = 10V$





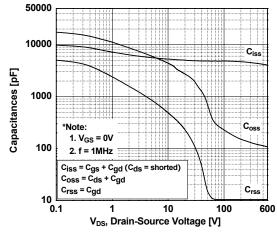
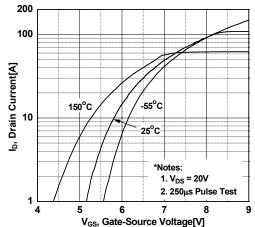


Figure 2. Transfer Characteristics





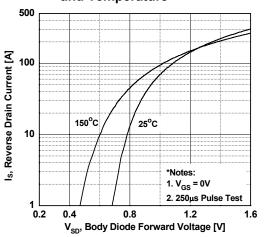
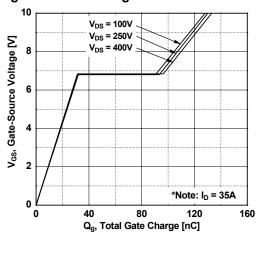
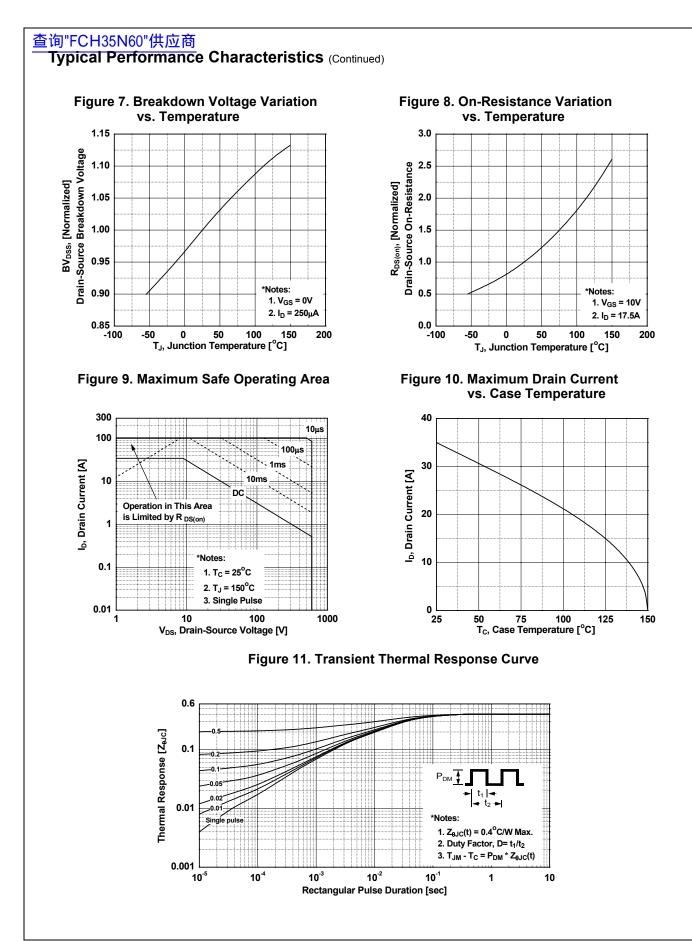
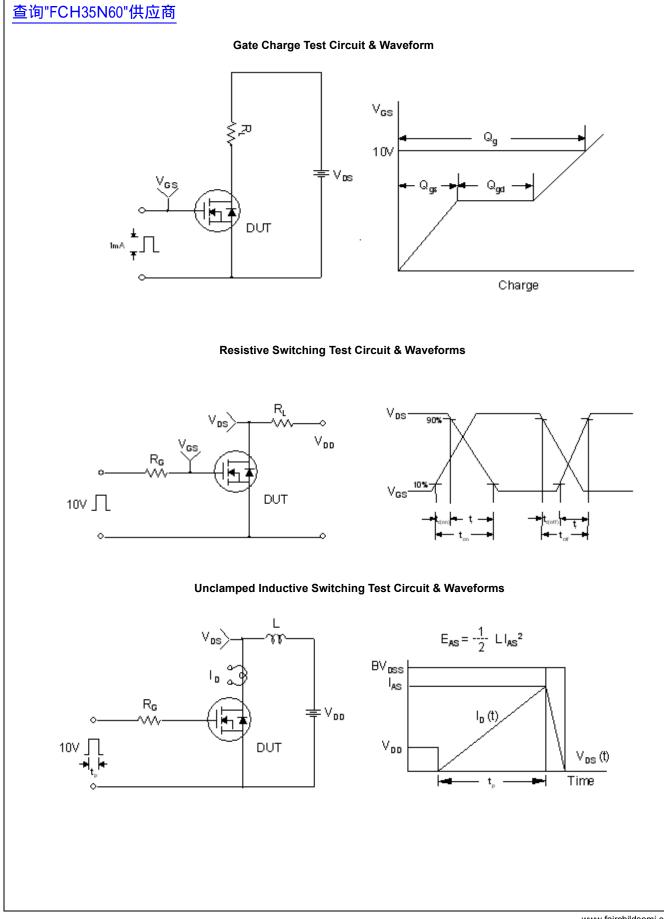


Figure 6. Gate Charge Characteristics



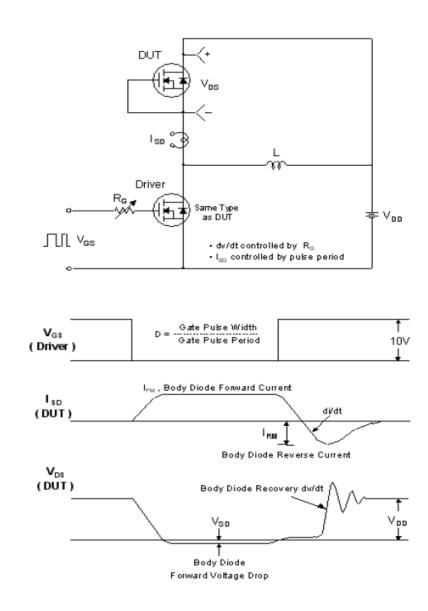


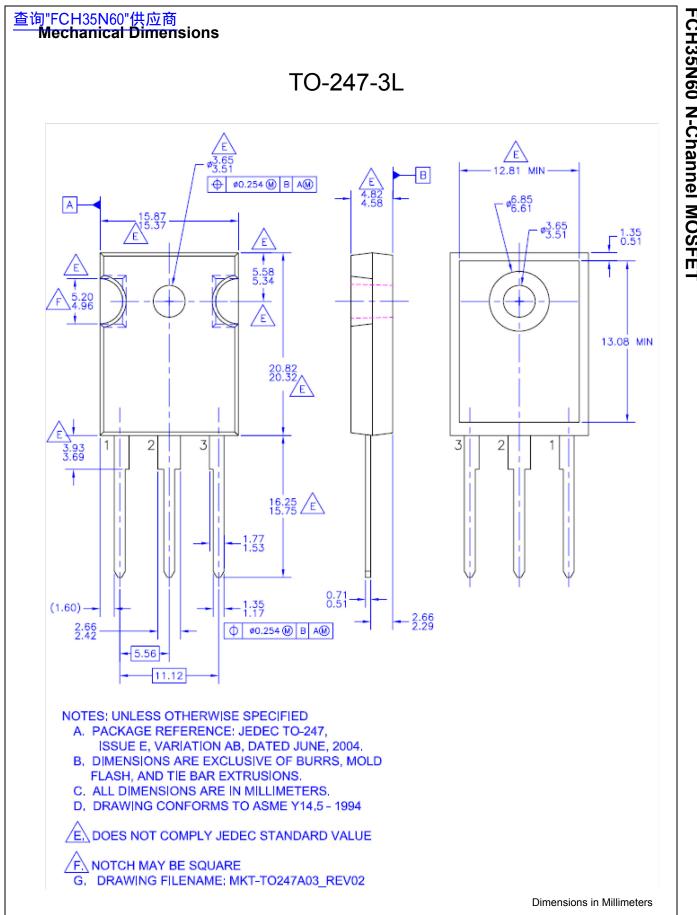
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Peak Diode Recovery dv/dt Test Circuit & Waveforms





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